Infineon Technologies - XMC1100T016X0016AAXUMA1 Datasheet

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I²C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, I²S, POR, PWM, WDT
Number of I/O	11
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 6x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	16-TSSOP (0.173", 4.40mm Width)
Supplier Device Package	PG-TSSOP-16-8
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xmc1100t016x0016aaxuma1

XMC1100

Microcontroller Series
for Industrial Applications

XMC1000 Family

ARM® Cortex™-M0
32-bit processor core

Data Sheet

V1.4 2014-05

Microcontrollers

About this Document

This Data Sheet is addressed to embedded hardware and software developers. It provides the reader with detailed descriptions about the ordering designations, available features, electrical and physical characteristics of the XMC1100 series devices.

The document describes the characteristics of a superset of the XMC1100 series devices. For simplicity, the various device types are referred to by the collective term XMC1100 throughout this document.

XMC1000 Family User Documentation

The set of user documentation includes:

- **Reference Manual**
  – decribes the functionality of the superset of devices.
- **Data Sheets**
  – list the complete ordering designations, available features and electrical characteristics of derivative devices.
- **Errata Sheets**
  – list deviations from the specifications given in the related Reference Manual or Data Sheets. Errata Sheets are provided for the superset of devices.

Attention: Please consult all parts of the documentation set to attain consolidated knowledge about your device.

Application related guidance is provided by **Users Guides** and **Application Notes**.

Please refer to **http://www.infineon.com/xmc1000** to get access to the latest versions of those documents.

1 Summary of Features

The XMC1100 devices are members of the XMC1000 family of microcontrollers based on the ARM Cortex-M0 processor core. The XMC1100 series devices are designed for general purpose applications.

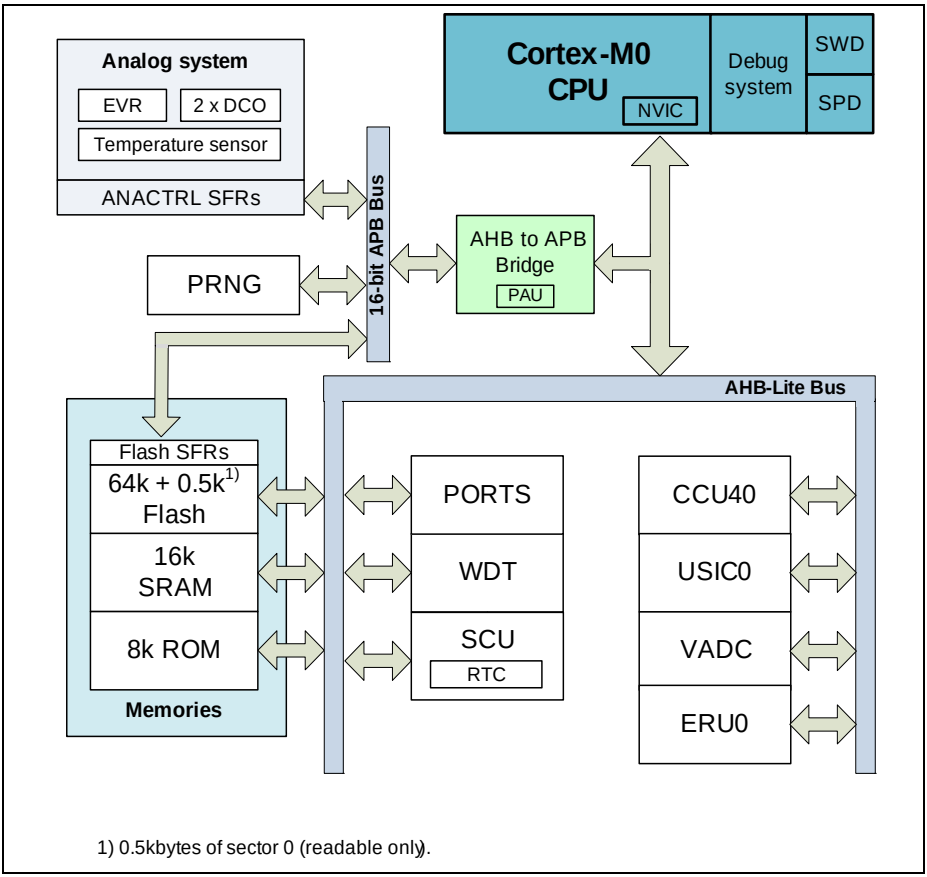

Figure 1 System Block Diagram

CPU Subsystem

- CPU Core
  - High Performance 32-bit ARM Cortex-M0 CPU
  - Most of 16-bit Thumb instruction set
  - Subset of 32-bit Thumb2 instruction set

Table 4 XMC1100 **Chip Identification Number**

Derivative	Value	Marking
XMC1100-T016F0008	00011032 01CF00FF 00001F37 00000000 00000B00 00001000 00003000 $101ED083_H$	AA
XMC1100-T016F0016	00011032 01CF00FF 00001F37 00000000 00000B00 00001000 00005000 $101ED083_H$	AA
XMC1100-T016F0032	00011032 01CF00FF 00001F37 00000000 00000B00 00001000 00009000 $101ED083_H$	AA
XMC1100-T016F0064	00011032 01CF00FF 00001F37 00000000 00000B00 00001000 00011000 $101ED083_H$	AA
XMC1100-T016X0064	00011033 01CF00FF 00001F37 00000000 00000B00 00001000 00011000 $101ED083_H$	AA
XMC1100-T038F0016	00011012 01CF00FF 00001F37 00000000 00000B00 00001000 00005000 $101ED083_H$	AA
XMC1100-T038F0032	00011012 01CF00FF 00001F37 00000000 00000B00 00001000 00009000 $101ED083_H$	AA
XMC1100-T038F0064	00011012 01CF00FF 00001F37 00000000 00000B00 00001000 00011000 $101ED083_H$	AA
XMC1100-T038X0064	00011013 01CF00FF 00001F37 00000000 00000B00 00001000 00011000 $101ED083_H$	AA
XMC1100-Q024F0008	00011062 01CF00FF 00001F37 00000000 00000B00 00001000 00003000 $101ED083_H$	AA
XMC1100-Q024F0016	00011062 01CF00FF 00001F37 00000000 00000B00 00001000 00005000 $101ED083_H$	AA
XMC1100-Q024F0032	00011062 01CF00FF 00001F37 00000000 00000B00 00001000 00009000 $101ED083_H$	AA
XMC1100-Q024F0064	00011062 01CF00FF 00001F37 00000000 00000B00 00001000 00011000 $101ED083_H$	AA
XMC1100-Q040F0016	00011042 01CF00FF 00001F37 00000000 00000B00 00001000 00005000 $101ED083_H$	AA
XMC1100-Q040F0032	00011042 01CF00FF 00001F37 00000000 00000B00 00001000 00009000 $101ED083_H$	AA
XMC1100-Q040F0064	00011042 01CF00FF 00001F37 00000000 00000B00 00001000 00011000 $101ED083_H$	AA

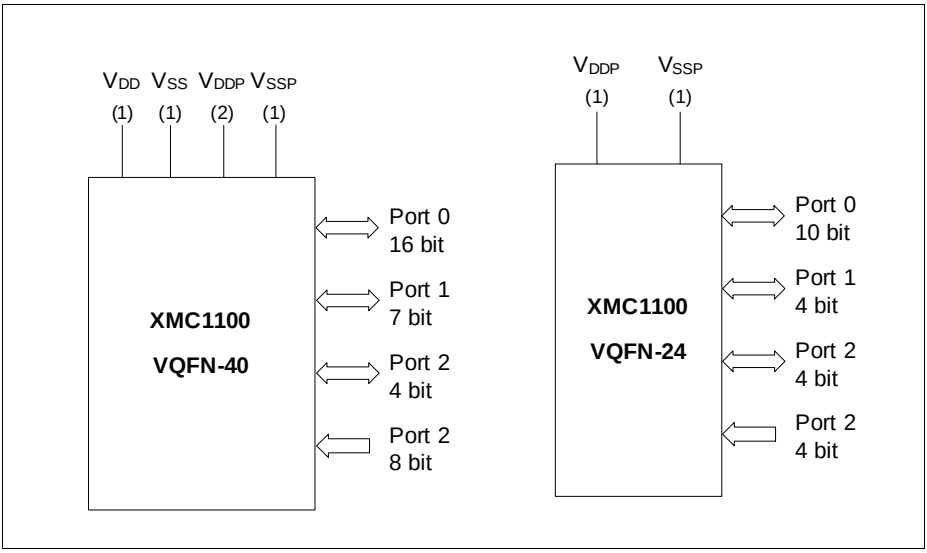

Figure 3 XMC1100 Logic Symbol for VQFN-24 and VQFN-40

2.2 Pin Configuration and Definition

The following figures summarize all pins, showing their locations on the different packages.

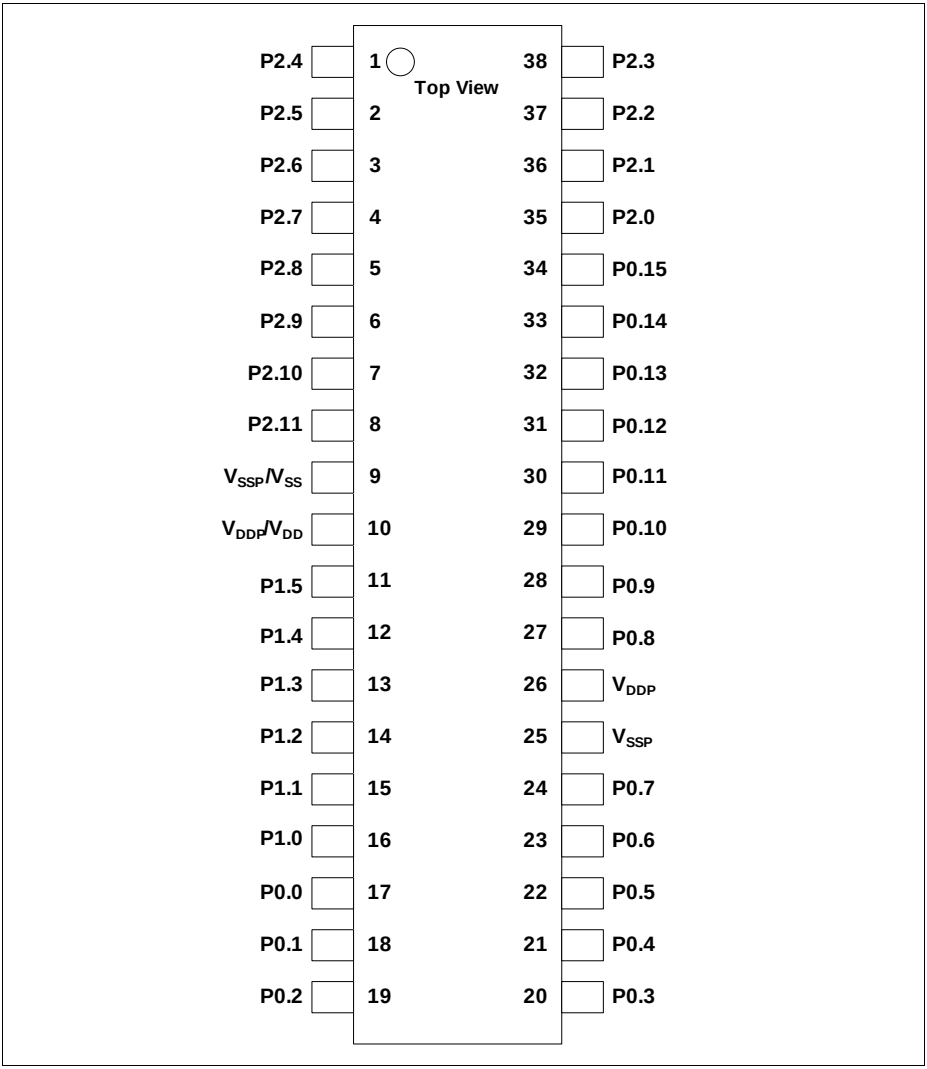

Figure 4 XMC1100 **PG-TSSOP-38 Pin Configuration** (top view)

3.1.2 Absolute Maximum Ratings

Stresses above the values listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions may affect device reliability.

Table 9 Absolute Maximum Rating Parameters

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
Junction temperature	T_J	SR	-40	–	115	°C	–
Storage temperature	T_S	SR	-40	–	125	°C	–
Voltage on power supply pin with respect to V_{SSP}	V_{DDP}	SR	-0.3	–	6	V	–
Voltage on any pin with respect to V_{SSP}	V_{IN}	SR	-0.5	–	V_{DDP} + 0.5 or max. 6	V	whichever is lower
Voltage on any analog input pin with respect to V_{SSP}	V_{AIN} V_{AREF}	SR	-0.5	–	V_{DDP} + 0.5 or max. 6	V	–
Input current on any pin during overload condition	I_{IN}	SR	-10	–	10	mA	–
Absolute sum of all input currents during overload condition	$\Sigma\|I_{IN}\|$	SR	–	–	50	mA	–
Analog comparator input voltage	V_{CM}	SR	-0.3	–	V_{DDP} + 0.3	V	

3.1.3 Operating Conditions

The following operating conditions must not be exceeded in order to ensure correct operation and reliability of the XMC1100. All parameters specified in the following tables refer to these operating conditions, unless noted otherwise.

Table 10 Operating Conditions Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Ambient Temperature	T_A SR	-40	–	85	°C	Temp. Range F
		-40	–	105	°C	Temp. Range X
Digital supply voltage[1)]	V_{DDP} SR	1.8	–	5.5	V	
MCLK Frequency	f_{MCLK} CC	–	–	33.2	MHz	CPU clock
PCLK Frequency	f_{PCLK} CC	–	–	66.4	MHz	Peripherals clock

1) See also the Supply Monitoring thresholds, **Chapter 3.3.3**.

3.2 DC Parameters

3.2.1 Input/Output Characteristics

Table 11 provides the characteristics of the input/output pins of the XMC1100.

Table 11 Input/Output Characteristics (Operating Conditions apply)

Parameter	Symbol		Limit Values		Unit	Test Conditions
			Min.	Max.		
Output low voltage on port pins (with standard pads)	V_{OLP}	CC	–	1.0	V	I_{OL} = 11 mA (5 V) I_{OL} = 7 mA (3.3 V)
			–	0.4	V	I_{OL} = 5 mA (5 V) I_{OL} = 3.5 mA (3.3 V)
Output low voltage on high current pads	V_{OLP1}	CC	–	1.0	V	I_{OL} = 50 mA (5 V) I_{OL} = 25 mA (3.3 V)
			–	0.32	V	I_{OL} = 10 mA (5 V)
			–	0.4	V	I_{OL} = 5 mA (3.3 V)
Output high voltage on port pins (with standard pads)	V_{OHP}	CC	V_{DDP} - 1.0	–	V	I_{OH} = -10 mA (5 V) I_{OH} = -7 mA (3.3 V)
			V_{DDP} - 0.4	–	V	I_{OH} = -4.5 mA (5 V) I_{OH} = -2.5 mA (3.3 V)
Output high voltage on high current pads	V_{OHP1}	CC	V_{DDP} - 0.32	–	V	I_{OH} = -6 mA (5 V)
			V_{DDP} - 1.0	–	V	I_{OH} = -8 mA (3.3 V)
			V_{DDP} - 0.4	–	V	I_{OH} = -4 mA (3.3 V)
Input low voltage on port pins (Standard Hysteresis)	V_{ILPS}	SR	–	0.19 × V_{DDP}	V	CMOS Mode (5 V, 3.3 V & 2.2 V)
Input high voltage on port pins (Standard Hysteresis)	V_{IHPS}	SR	0.7 × V_{DDP}	–	V	CMOS Mode (5 V, 3.3 V & 2.2 V)
Input low voltage on port pins (Large Hysteresis)	V_{ILPL}	SR	–	0.08 × V_{DDP}	V	CMOS Mode (5 V, 3.3 V & 2.2 V)[3)]

Table 12 ADC Characteristics (Operating Conditions apply) (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Maximum sample rate in 8-bit mode [3]	f_{C8} CC	–	–	f_{ADC} / 38.5	–	1 sample pending
		–	–	f_{ADC} / 54.5	–	2 samples pending
DNL error	EA_{DNL} CC	–	±2.0	–	LSB 12	
INL error	EA_{INL} CC	–	±4.0	–	LSB 12	
Gain error with external reference	EA_{GAIN} CC	–	±0.5	–	%	SHSCFG.AREF = 00_B (calibrated)
Gain error with internal reference	EA_{GAIN} CC	–	±3.6	–	%	SHSCFG.AREF = $1X_B$ (calibrated), -40°C - 105°C
		–	±2.0	–	%	SHSCFG.AREF = $1X_B$ (calibrated), 0°C - 85°C
Offset error	EA_{OFF} CC	–	±6.0	–	LSB 12	Calibrated

1) Not subject to production test, verified by design/characterization.

2) No pending samples assumed, excluding sampling time and calibration.

3) Includes synchronization and calibration (average of gain and offset calibration).

3.2.4 Power Supply Current

The total power supply current defined below consists of a leakage and a switching component.

Application relevant values are typically lower than those given in the following tables, and depend on the customer's system operating conditions (e.g. thermal connection or used application configurations).

Table 14 Power Supply Parameters[1)]

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.[2)]	Max.		
Active mode current[3)]	I_{DDPA} CC	–	8.4	11.0	mA	f_{MCLK} = 32 MHz f_{PCLK} = 64 MHz
		–	3.7	–	mA	f_{MCLK} = 1 MHz f_{PCLK} = 1 MHz
Sleep mode current Peripherals clock enabled[4)]	I_{DDPSE} CC	–	5.9	–	mA	f_{MCLK} = 32 MHz f_{PCLK} = 64 MHz
Sleep mode current Peripherals clock disabled[5)]	I_{DDPSD} CC	–	1.2	–	mA	f_{MCLK} = 1 MHz f_{PCLK} = 1 MHz
Deep Sleep mode current[6)]	I_{DDPDS} CC	–	0.24	–	mA	
Wake-up time from Sleep to Active mode[7)]	t_{SSA} CC	–	6	–	cycles	
Wake-up time from Deep Sleep to Active mode[8)]	t_{DSA} CC	–	280	–	µsec	

1) Not all parameters are 100% tested, but are verified by design/characterisation and test correlation.
2) The typical values are measured at T_A = + 25 °C and V_{DDP} = 5 V.
3) CPU and all peripherals clock enabled, Flash is in active mode.
4) CPU is sleep, all peripherals clock enabled and Flash is in active mode.
5) CPU is sleep, Flash is powered down and code executed from RAM after wake-up.
6) CPU is sleep, peripherals clock disabled, Flash is powered down and code executed from RAM after wake-up.
7) CPU is sleep, Flash is in active mode during sleep mode.
8) CPU is sleep, Flash is in power down mode during deep sleep mode.

Table 15 provides the active current consumption of some modules operating at 5 V power supply at 25 °C. The typical values shown are used as a reference guide on the current consumption when these modules are enabled.

Table 15 Typical Active Current Consumption[1)]

Active Current Consumption	Symbol	Limit Values	Unit	Test Condition
		Typ.		
Baseload current	I_{CPUDDC}	5.04	mA	Modules including Core, SCU, PORT, memories, ANATOP[2)]
VADC and SHS	I_{ADCDDC}	3.4	mA	Set CGATCLR0.VADC to 1[3)]
USIC0	$I_{USIC0DDC}$	0.87	mA	Set CGATCLR0.USIC0 to 1[4)]
CCU40	$I_{CCU40DDC}$	0.94	mA	Set CGATCLR0.CCU40 to 1[5)]
WDT	I_{WDTDDC}	0.03	mA	Set CGATCLR0.WDT to 1[6)]
RTC	I_{RTCDDC}	0.01	mA	Set CGATCLR0.RTC to 1[7)]

1) Not subject to production test, verified by design/characterisation.

2) Baseload current is measured with device running in user mode, MCLK=PCLK=32 MHz, with an endless loop in the flash memory. The clock to the modules stated in CGATSTAT0 are gated.

3) Active current is measured with: module enabled, MCLK=32 MHz, running in auto-scan conversion mode

4) Active current is measured with: module enabled, alternating messages sent to PC at 57.6kbaud every 200ms

5) Active current is measured with: module enabled, MCLK=PCLK=32 MHz, 1 CCU4 slice for PWM switching from 1500Hz and 1000Hz at regular intervals, 1 CCU4 slice in capture mode for reading period and duty cycle

6) Active current is measured with: module enabled, MCLK=32 MHz, time-out mode; WLB = 0, WUB = 0x00008000; WDT serviced every 1s

7) Active current is measured with: module enabled, MCLK=32 MHz, Periodic interrupt enabled

3.3.2 Output Rise/Fall Times

Table 17 provides the characteristics of the output rise/fall times in the XMC1100. **Figure 9** describes the rise time and fall time parameters.

Table 17 Output Rise/Fall Times Parameters (Operating Conditions apply)

Parameter	Symbol	Limit Values		Unit	Test Conditions
		Min.	Max.		
Rise/fall times on High Current Pad[1)2)]	t_{HCPR}, t_{HCPF}	–	9	ns	50 pF @ 5 V[3)]
		–	12	ns	50 pF @ 3.3 V[4)]
		–	25	ns	50 pF @ 1.8 V[5)]
Rise/fall times on Standard Pad[1)2)]	t_R, t_F	–	12	ns	50 pF @ 5 V[6)]
		–	15	ns	50 pF @ 3.3 V[7)].
		–	31	ns	50 pF @ 1.8 V[8)].

1) Rise/Fall time parameters are taken with 10% - 90% of supply.
2) Not all parameters are 100% tested, but are verified by design/characterisation and test correlation.
3) Additional rise/fall time valid for C_L = 50 pF - C_L = 100 pF @ 0.150 ns/pF at 5 V supply voltage.
4) Additional rise/fall time valid for C_L = 50 pF - C_L = 100 pF @ 0.205 ns/pF at 3.3 V supply voltage.
5) Additional rise/fall time valid for C_L = 50 pF - C_L = 100 pF @ 0.445 ns/pF at 1.8 V supply voltage.
6) Additional rise/fall time valid for C_L = 50 pF - C_L = 100 pF @ 0.225 ns/pF at 5 V supply voltage.
7) Additional rise/fall time valid for C_L = 50 pF - C_L = 100 pF @ 0.288 ns/pF at 3.3 V supply voltage.
8) Additional rise/fall time valid for C_L = 50 pF - C_L = 100 pF @ 0.588 ns/pF at 1.8 V supply voltage.

3) Valid for a 100 nF buffer capacitor connected to supply pin where current from capacitor is forwarded only to the chip. A larger capacitor value has to be chosen if the power source sink a current.

4) This values does not include the ramp-up time. During startup firmware execution, MCLK is running at 32 MHz and the clocks to peripheral as specified in register CGATSTAT0 are gated.

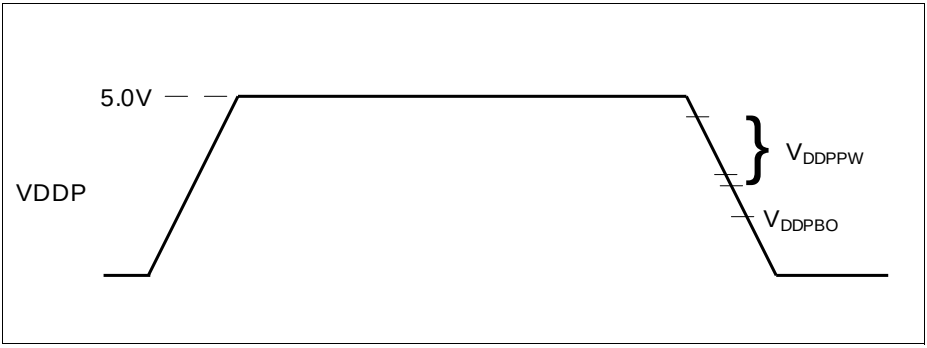

Figure 12 Supply Threshold Parameters

3.3.4 On-Chip Oscillator Characteristics

Table 19 provides the characteristics of the 64 MHz clock output from the digital controlled oscillator, DCO1 in XMC1100.

Table 19 64 MHz DCO1 Characteristics (Operating Conditions apply)

Parameter	Symbol		Limit Values			Unit	Test Conditions
			Min.	Typ.	Max.		
Nominal frequency	f_{NOM}	CC	63.5	64	64.5	MHz	under nominal conditions[1] after trimming
Accuracy	Δf_{LT}	CC	-1.7	–	3.4	%	with respect to f_{NOM}(typ), over temperature (0 °C to 85 °C)[2]
			-3.9	–	4.0	%	with respect to f_{NOM}(typ), over temperature (-40 °C to 105 °C)[2]
Accuracy with calibration based on temperature sensor	Δf_{LTT}	CC	-1.3	–	1.25	%	with respect to f_{NOM}(typ), over temperature (T_A = 0 °C to 105 °C)[2]
			-2.6	–	1.25	%	with respect to f_{NOM}(typ), over temperature (T_A = -40 °C to 105 °C)[2]

1) The deviation is relative to the factory trimmed frequency at nominal V_{DDC} and T_A = + 25 °C.

2) Not subject to production test, verified by design/characterisation.

3.3.5 Serial Wire Debug Port (SW-DP) Timing

The following parameters are applicable for communication through the SW-DP interface.

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 21 SWD Interface Timing Parameters(Operating Conditions apply)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
SWDCLK high time	t_1 SR	50	–	500000	ns	–
SWDCLK low time	t_2 SR	50	–	500000	ns	–
SWDIO input setup to SWDCLK rising edge	t_3 SR	10	–	–	ns	–
SWDIO input hold after SWDCLK rising edge	t_4 SR	10	–	–	ns	–
SWDIO output valid time after SWDCLK rising edge	t_5 CC	–	–	68	ns	C_L = 50 pF
		–	–	62	ns	C_L = 30 pF
SWDIO output hold time from SWDCLK rising edge	t_6 CC	4	–	–	ns	

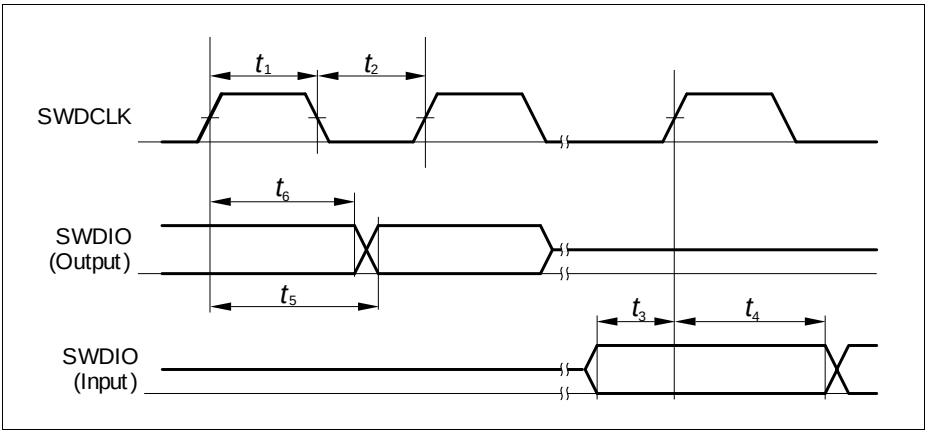

Figure 14 SWD Timing

3.3.6 SPD Timing Requirements

The optimum SPD decision time between 0_B and 1_B is 0.75 µs. With this value the system has maximum robustness against frequency deviations of the sampling clock on tool and on device side. However it is not always possible to exactly match this value with the given constraints for the sample clock. For instance for a oversampling rate of 4, the sample clock will be 8 MHz and in this case the closest possible effective decision time is 5.5 clock cycles (0.69 µs).

Table 22 Optimum Number of Sample Clocks for SPD

Sample Freq.	Sampling Factor	Sample Clocks 0_B	Sample Clocks 1_B	Effective Decision Time[1)]	Remark
8 MHz	4	1 to 5	6 to 12	0.69 µs	The other closest option (0.81 µs) for the effective decision time is less robust.

1) Nominal sample frequency period multiplied with 0.5 + (max. number of 0_B sample clocks)

For a balanced distribution of the timing robustness of SPD between tool and device, the timing requirements for the tool are:

- Frequency deviation of the sample clock is +/- 5%
- Effective decision time is between 0.69 µs and 0.75 µs (calculated with nominal sample frequency)

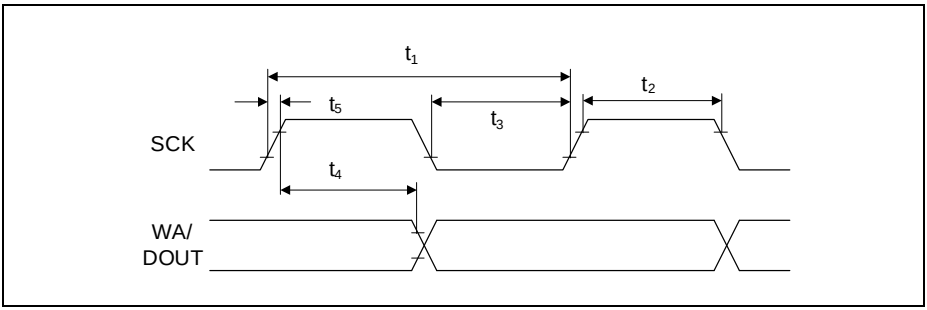

Figure 17 USIC IIS Master Transmitter Timing

Table 28 USIC IIS Slave Receiver Timing

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Clock period	t_6 SR	$4/f_{MCLK}$	-	-	ns	
Clock HIGH	t_7 SR	0.35 x t_{6min}	-	-	ns	
Clock Low	t_8 SR	0.35 x t_{6min}	-	-	ns	
Set-up time	t_9 SR	0.2 x t_{6min}	-	-	ns	
Hold time	t_{10} SR	10	-	-	ns	

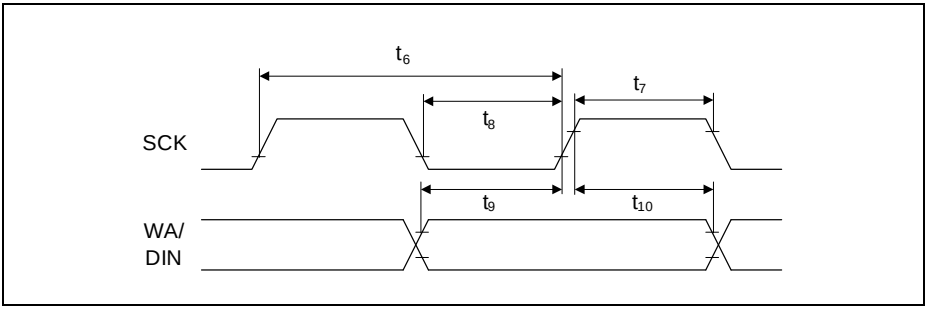

Figure 18 USIC IIS Slave Receiver Timing

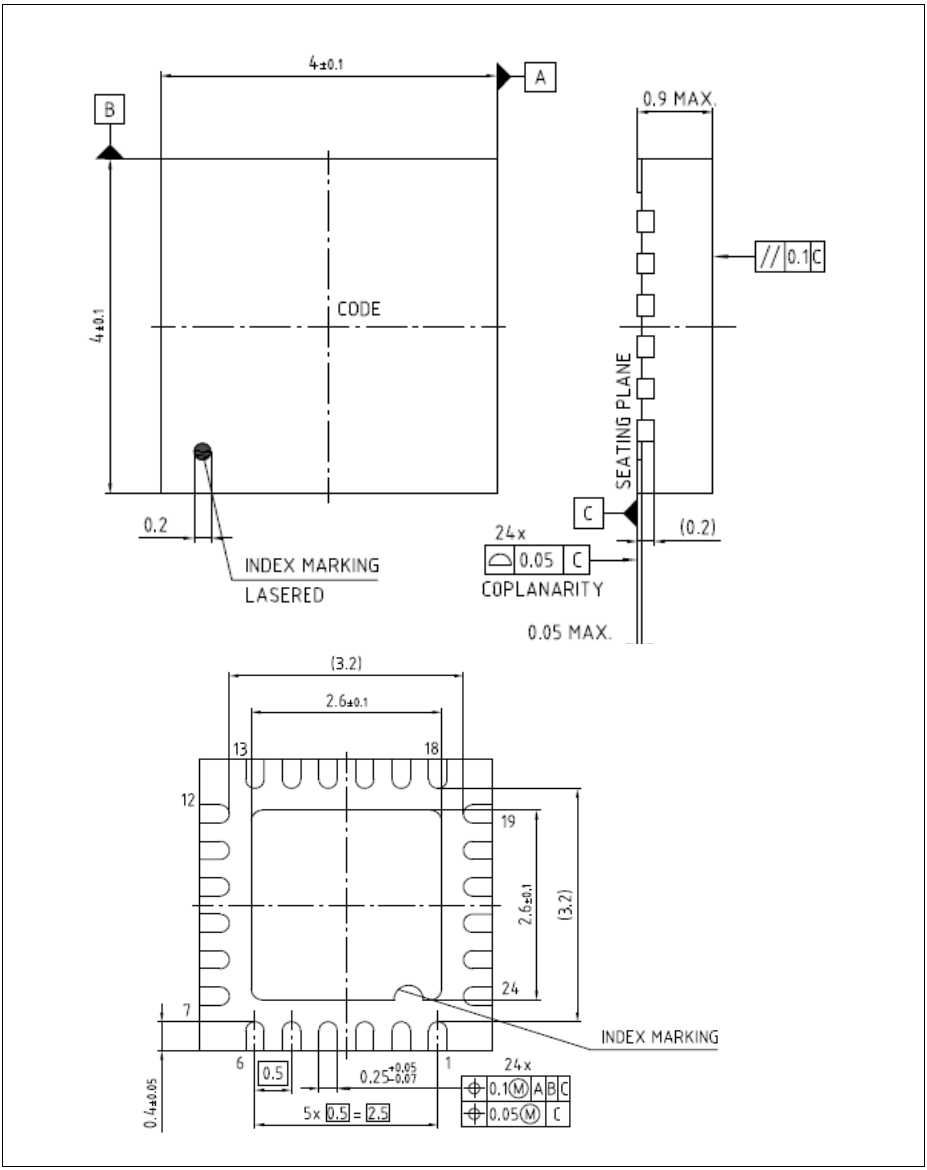

Figure 21 PG-VQFN-24-19

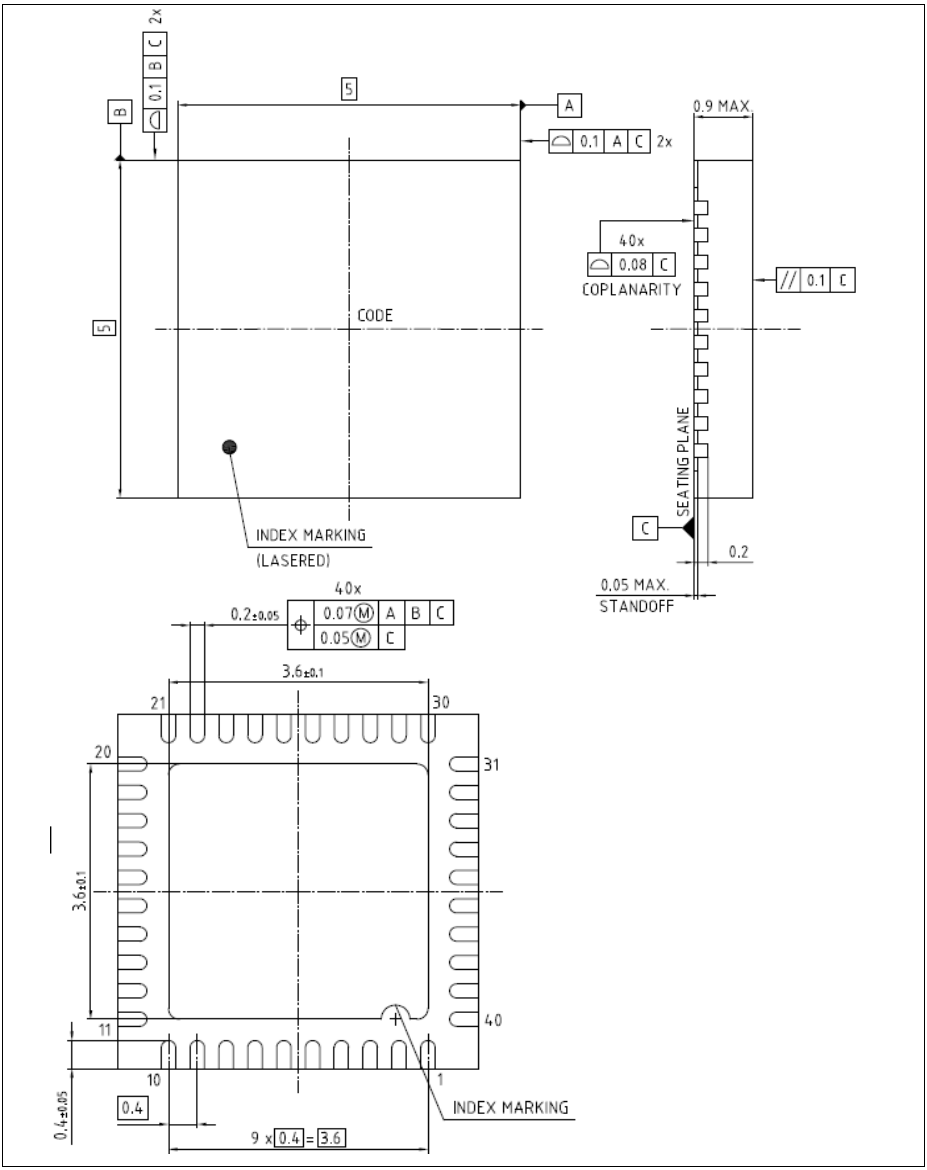

Figure 22 PG-VQFN-40-13

All dimensions in mm.